# Low-power 2-input NAND gate (open drain) Rev. 6 — 28 June 2012

Product data sheet

#### **General description** 1.

The 74AUP1G38 provides the single 2-input NAND gate with open-drain output. The output of the device is an open drain and can be connected to other open-drain outputs to implement active-LOW wired-OR or active-HIGH wired-AND functions.

Schmitt trigger action at all inputs makes the circuit tolerant to slower input rise and fall times across the entire  $V_{CC}$  range from 0.8 V to 3.6 V.

This device ensures a very low static and dynamic power consumption across the entire V<sub>CC</sub> range from 0.8 V to 3.6 V.

This device is fully specified for partial power-down applications using I<sub>OFF</sub>. The I<sub>OFF</sub> circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

#### 2. **Features and benefits**

- Wide supply voltage range from 0.8 V to 3.6 V
- High noise immunity
- Complies with JEDEC standards:
  - JESD8-12 (0.8 V to 1.3 V)
  - JESD8-11 (0.9 V to 1.65 V)
  - JESD8-7 (1.2 V to 1.95 V)
  - JESD8-5 (1.8 V to 2.7 V)
  - JESD8-B (2.7 V to 3.6 V)
- ESD protection:
  - HBM JESD22-A114F Class 3A exceeds 5000 V
  - MM JESD22-A115-A exceeds 200 V
  - CDM JESD22-C101E exceeds 1000 V
- Low static power consumption;  $I_{CC} = 0.9 \,\mu A$  (maximum)
- Latch-up performance exceeds 100 mA per JESD 78 Class II
- Inputs accept voltages up to 3.6 V
- Low noise overshoot and undershoot < 10 % of V<sub>CC</sub>
- I<sub>OFF</sub> circuitry provides partial power-down mode operation
- Multiple package options
- Specified from -40 °C to +85 °C and -40 °C to +125 °C



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#### **Ordering information** 3.

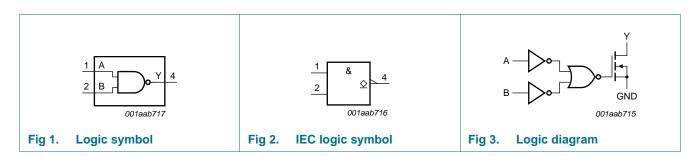
Type number	Package	Package									
	Temperature range	Name	Description	Version							
74AUP1G38GW	–40 °C to +125 °C	TSSOP5	plastic thin shrink small outline package; 5 leads; body width 1.25 mm	SOT353-1							
74AUP1G38GM	–40 °C to +125 °C	XSON6	plastic extremely thin small outline package; no leads; 6 terminals; body 1 $\times$ 1.45 $\times$ 0.5 mm	SOT886							
74AUP1G38GF	–40 °C to +125 °C	XSON6	plastic extremely thin small outline package; no leads; 6 terminals; body 1 $\times$ 1 $\times$ 0.5 mm	SOT891							
74AUP1G38GN	–40 °C to +125 °C	XSON6	extremely thin small outline package; no leads; 6 terminals; body $0.9 \times 1.0 \times 0.35$ mm	SOT1115							
74AUP1G38GS	–40 °C to +125 °C	XSON6	extremely thin small outline package; no leads; 6 terminals; body $1.0 \times 1.0 \times 0.35$ mm	SOT1202							
74AUP1G38GX	–40 °C to +125 °C	X2SON5	X2SON5: plastic thermal enhanced extremely thin small outline package; no leads; 5 terminals; body $0.8 \times 0.8 \times 0.35$ mm	SOT1226							

#### **Marking** 4.

Table 2. Marking	
Type number	Marking code <sup>[1]</sup>
74AUP1G38GW	aB
74AUP1G38GM	aB
74AUP1G38GF	aB
74AUP1G38GN	aB
74AUP1G38GS	aB
74AUP1G38GX	aB

[1] The pin 1 indicator is located on the lower left corner of the device, below the marking code.

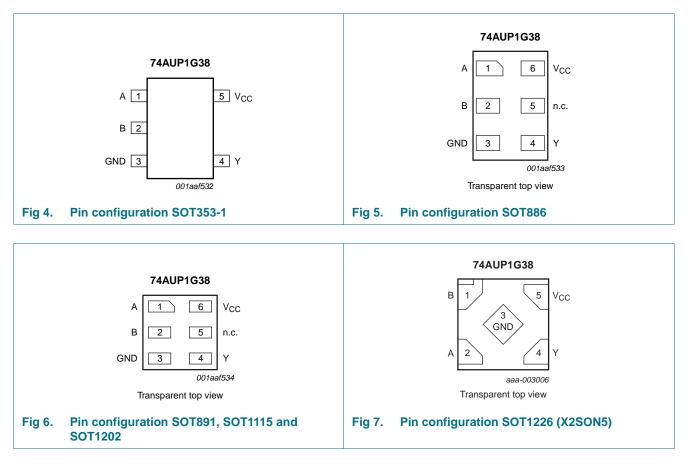
#### **Functional diagram** 5.



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#### **Pinning information** 6.

## 6.1 Pinning



## 6.2 Pin description

Table 3. Pin description							
Symbol	Pin		Description				
	TSSOP5 and X2SO	N5 XSON6					
А	1	1	data input				
В	2	2	data input				
GND	3	3	ground (0 V)				
Y	4	4	data output				
n.c.	-	5	not connected				
V <sub>CC</sub>	5	6	supply voltage				

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#### **Functional description** 7.

#### Table 4. Function table<sup>[1]</sup>

Input		Output
Α	В	Y
L	L	Z
L	Н	Z
Н	L	Z
Н	Н	L

[1] H = HIGH voltage level;

L = LOW voltage level;

Z = high-impedance OFF state.

#### **Limiting values** 8.

#### Table 5. **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		-0.5	+4.6	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	-50	-	mA
VI	input voltage		<u>[1]</u> –0.5	+4.6	V
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-50	-	mA
Vo	output voltage	Active mode and Power-down mode	<u>[1]</u> –0.5	+4.6	V
Ι <sub>Ο</sub>	output current	$V_{O} = 0 V$ to $V_{CC}$	-	+20	mA
I <sub>CC</sub>	supply current		-	+50	mA
I <sub>GND</sub>	ground current		-50	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{amb}$ = -40 °C to +125 °C	[2] _	250	mW

[1] The minimum input and output voltage ratings may be exceeded if the input and output current ratings are observed.

For TSSOP5 packages: above 87.5 °C the value of Ptot derates linearly with 4.0 mW/K. [2]

For XSON6 and X2SON5 packages: above 118 °C the value of Ptot derates linearly with 7.8 mW/K.

#### **Recommended operating conditions** 9.

Table 6.	Recommended operating conditi	ons			
Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		0.8	3.6	V
VI	input voltage		0	3.6	V
Vo	output voltage	Active mode and Power-down mode	0	3.6	V
T <sub>amb</sub>	ambient temperature		-40	+125	°C
$\Delta t / \Delta V$	input transition rise and fall rate	$V_{CC} = 0.8 \text{ V} \text{ to } 3.6 \text{ V}$	0	200	ns/V

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## **10. Static characteristics**

### Table 7. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
T <sub>amb</sub> = 2	5 °C					
VIH	HIGH-level input voltage	$V_{CC} = 0.8 V$	$0.70\times V_{CC}$	-	-	V
		$V_{CC} = 0.9 V$ to 1.95 V	$0.65 \times V_{CC}$	-	-	V
		$V_{CC}$ = 2.3 V to 2.7 V	1.6	-	-	V
		$V_{CC} = 3.0 \text{ V} \text{ to } 3.6 \text{ V}$	2.0	-	-	V
VIL	LOW-level input voltage	$V_{CC} = 0.8 V$	-	-	$0.30\times V_{CC}$	V
		$V_{CC} = 0.9 V$ to 1.95 V	-	-	$0.35 \times V_{CC}$	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	-	-	0.7	V
		$V_{CC} = 3.0 \text{ V} \text{ to } 3.6 \text{ V}$	-	-	0.9	V
V <sub>OL</sub>	LOW-level output voltage	$V_I = V_{IH} \text{ or } V_{IL}$				
		$I_{O}$ = 20 $\mu$ A; $V_{CC}$ = 0.8 V to 3.6 V	-	-	0.1	V
		I <sub>O</sub> = 1.1 mA; V <sub>CC</sub> = 1.1 V	-	-	$0.3\times V_{CC}$	V
		I <sub>O</sub> = 1.7 mA; V <sub>CC</sub> = 1.4 V	-	-	0.31	V
		I <sub>O</sub> = 1.9 mA; V <sub>CC</sub> = 1.65 V	-	-	0.31	V
		$I_0 = 2.3 \text{ mA}; V_{CC} = 2.3 \text{ V}$	-	-	0.31	V
		I <sub>O</sub> = 3.1 mA; V <sub>CC</sub> = 2.3 V	-	-	0.44	V
		I <sub>O</sub> = 2.7 mA; V <sub>CC</sub> = 3.0 V	-	-	0.31	V
		$I_0 = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.44	V
lı –	input leakage current	$V_1 = GND$ to 3.6 V; $V_{CC} = 0$ V to 3.6 V	-	-	±0.1	μA
l <sub>oz</sub>	OFF-state output current	$V_I = V_{IH}$ or $V_{IL}$ (and at least one input LOW); $V_O = 0$ V to 3.6 V; $V_{CC} = 0$ V to 3.6 V	-	-	±0.1	μΑ
I <sub>OFF</sub>	power-off leakage current	$V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC} = 0$ V	-	-	±0.2	μA
$\Delta I_{OFF}$	additional power-off leakage current	$V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC} = 0$ V to 0.2 V	-	-	±0.2	μΑ
I <sub>CC</sub>	supply current	$V_{I} = GND \text{ or } V_{CC}; I_{O} = 0 \text{ A};$ $V_{CC} = 0.8 \text{ V to } 3.6 \text{ V}$	-	-	0.5	μΑ
Δl <sub>CC</sub>	additional supply current	$V_{I} = V_{CC} - 0.6 \text{ V}; I_{O} = 0 \text{ A}; V_{CC} = 3.3 \text{ V}$	-	-	40	μA
CI	input capacitance	$V_{CC}$ = 0 V to 3.6 V; $V_{I}$ = GND or $V_{CC}$	-	0.8	-	pF
Co	output capacitance	output enabled; $V_0 = GND$ ; $V_{CC} = 0 V$	-	1.7	-	pF
		output disabled; $V_O = GND$ ; $V_{CC} = 0 V$	-	1.1	-	pF
T <sub>amb</sub> = -	40 °C to +85 °C					
VIH	HIGH-level input voltage	$V_{CC} = 0.8 V$	$0.70 \times V_{CC}$	-	-	V
		$V_{CC} = 0.9 V$ to 1.95 V	$0.65 \times V_{CC}$	-	-	V
		$V_{CC} = 2.3 V \text{ to } 2.7 V$	1.6	-	-	V
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	2.0	-	-	V

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>IL</sub>	LOW-level input voltage	$V_{CC} = 0.8 V$	-	-	$0.30\times V_{CC}$	V
		$V_{CC} = 0.9 V$ to 1.95 V	-	-	$0.35 \times V_{CC}$	V
		$V_{CC}$ = 2.3 V to 2.7 V	-	-	0.7	V
		$V_{CC} = 3.0 V \text{ to } 3.6 V$	-	-	0.9	V
V <sub>OL</sub>	LOW-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$				
		$I_O$ = 20 $\mu A;V_{CC}$ = 0.8 V to 3.6 V	-	-	0.1	V
		I <sub>O</sub> = 1.1 mA; V <sub>CC</sub> = 1.1 V	-	-	$0.3\times V_{CC}$	V
		$I_{O}$ = 1.7 mA; $V_{CC}$ = 1.4 V	-	-	0.37	V
		I <sub>O</sub> = 1.9 mA; V <sub>CC</sub> = 1.65 V	-	-	0.35	V
		$I_{O}$ = 2.3 mA; $V_{CC}$ = 2.3 V	-	-	0.33	V
		$I_0 = 3.1 \text{ mA}; V_{CC} = 2.3 \text{ V}$	-	-	0.45	V
		$I_0 = 2.7 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.33	V
		$I_0 = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.45	V
l <sub>I</sub>	input leakage current	$V_I = GND$ to 3.6 V; $V_{CC} = 0$ V to 3.6 V	-	-	±0.5	μA
l <sub>oz</sub>	OFF-state output current	$V_{\rm I}$ = $V_{\rm IH}$ or $V_{\rm IL}$ (and at least one input LOW); $V_{\rm O}$ = 0 V to 3.6 V; $V_{\rm CC}$ = 0 V to 3.6 V	-	-	±0.5	μA
OFF	power-off leakage current	$V_{I} \text{ or } V_{O}$ = 0 V to 3.6 V; $V_{CC}$ = 0 V	-	-	±0.5	μΑ
∆l <sub>OFF</sub>	additional power-off leakage current	$V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC} = 0$ V to 0.2 V	-	-	±0.6	μΑ
сс	supply current	$V_{I} = GND \text{ or } V_{CC}; I_{O} = 0 \text{ A};$ $V_{CC} = 0.8 \text{ V to } 3.6 \text{ V}$	-	-	0.9	μΑ
Δl <sub>CC</sub>	additional supply current	$V_{I} = V_{CC} - 0.6 \text{ V}; I_{O} = 0 \text{ A}; V_{CC} = 3.3 \text{ V}$	-	-	50	μA
T <sub>amb</sub> = -	40 °C to +125 °C					
VIH	HIGH-level input voltage	$V_{CC} = 0.8 V$	$0.75\times V_{CC}$	-	-	V
		$V_{CC} = 0.9 V$ to 1.95 V	$0.70 \times V_{CC}$	-	-	V
		$V_{CC}$ = 2.3 V to 2.7 V	1.6	-	-	V
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	2.0	-	-	V
V <sub>IL</sub>	LOW-level input voltage	$V_{CC} = 0.8 V$	-	-	$0.25\times V_{CC}$	V
		$V_{CC} = 0.9 V$ to 1.95 V	-	-	$0.30\times V_{CC}$	V
		$V_{CC}$ = 2.3 V to 2.7 V	-	-	0.7	V
		$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	-	-	0.9	V
V <sub>OL</sub>	LOW-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$				
		$I_{O}$ = 20 $\mu$ A; $V_{CC}$ = 0.8 V to 3.6 V	-	-	0.11	V
		I <sub>O</sub> = 1.1 mA; V <sub>CC</sub> = 1.1 V	-	-	$0.33 \times V_{CC}$	V
		$I_{O}$ = 1.7 mA; $V_{CC}$ = 1.4 V	-	-	0.41	V
		$I_{O}$ = 1.9 mA; $V_{CC}$ = 1.65 V	-	-	0.39	V
		$I_{O}$ = 2.3 mA; $V_{CC}$ = 2.3 V	-	-	0.36	V
		$I_{O}$ = 3.1 mA; $V_{CC}$ = 2.3 V	-	-	0.50	V
		$I_0 = 2.7 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.36	V
		$I_0 = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.50	V

### Table 7. Static characteristics ...continued

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### Low-power 2-input NAND gate (open drain)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
l <sub>l</sub>	input leakage current	$V_{\rm I}$ = GND to 3.6 V; $V_{\rm CC}$ = 0 V to 3.6 V	-	-	±0.75	μΑ
I <sub>OZ</sub>	OFF-state output current	$V_{\rm I}$ = $V_{\rm IH}$ or $V_{\rm IL}$ (and at least one input LOW); $V_{\rm O}$ = 0 V to 3.6 V; $V_{\rm CC}$ = 0 V to 3.6 V	-	-	±0.75	μA
I <sub>OFF</sub>	power-off leakage current	$V_{I} \text{ or } V_{O}$ = 0 V to 3.6 V; $V_{CC}$ = 0 V	-	-	±0.75	μA
$\Delta I_{OFF}$	additional power-off leakage current	$V_1$ or $V_0 = 0$ V to 3.6 V; $V_{CC} = 0$ V to 0.2 V	-	-	±0.75	μΑ
I <sub>CC</sub>	supply current	$V_{I} = GND \text{ or } V_{CC}; I_{O} = 0 \text{ A};$ $V_{CC} = 0.8 \text{ V to } 3.6 \text{ V}$	-	-	1.4	μΑ
$\Delta I_{CC}$	additional supply current	$V_{I} = V_{CC} - 0.6 \text{ V}; I_{O} = 0 \text{ A}; V_{CC} = 3.3 \text{ V}$	-	-	75	μA

### Table 7. Static characteristics ...continued

## 11. Dynamic characteristics

### Table 8. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V; for test circuit see Figure 9

Symbol	Parameter	Conditions			25 °C		-40	0 °C to +1	25 °C	Unit
			-	Min	Typ <mark>[1]</mark>	Мах	Min	Max (85 °C)	Max (125 °C)	_
C <sub>L</sub> = 5 p	F									
t <sub>pd</sub>	propagation delay	A or B to Y; see Figure 8	[2]							
		$V_{CC} = 0.8 V$		-	13.5	-	-	-	-	ns
		$V_{CC}$ = 1.1 V to 1.3 V		1.9	4.6	10.4	1.8	11.4	12.6	ns
		$V_{CC}$ = 1.4 V to 1.6 V		1.5	3.3	6.5	1.4	7.4	8.2	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V		1.2	2.9	5.1	1.1	5.9	6.5	ns
		$V_{CC}$ = 2.3 V to 2.7 V		1.0	2.2	3.8	0.9	4.5	4.9	ns
		$V_{CC} = 3.0 \text{ V} \text{ to } 3.6 \text{ V}$		0.9	2.3	4.0	0.8	4.5	4.9	ns
C <sub>L</sub> = 10	pF									
t <sub>pd</sub>	propagation delay	A or B to Y; see Figure 8	[2]							
		$V_{CC} = 0.8 V$		-	16.3	-	-	-	-	ns
		$V_{CC} = 1.1 \text{ V} \text{ to } 1.3 \text{ V}$		2.3	5.6	12.3	2.1	13.7	15.1	ns
		$V_{CC}$ = 1.4 V to 1.6 V		1.8	4.1	7.6	1.7	8.8	9.7	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V		1.6	3.8	6.1	1.4	7.1	7.8	ns
		$V_{CC}$ = 2.3 V to 2.7 V		1.4	2.9	4.6	1.2	5.4	5.9	ns
		$V_{CC}$ = 3.0 V to 3.6 V		1.3	3.2	5.7	1.1	6.4	7.0	ns
C <sub>L</sub> = 15	pF									
t <sub>pd</sub>	propagation delay	A or B to Y; see Figure 8	[2]							
		$V_{CC} = 0.8 V$		-	19.0	-	-	-	-	ns
		$V_{CC} = 1.1 \text{ V} \text{ to } 1.3 \text{ V}$		2.6	6.6	14.2	2.4	15.8	17.4	ns
		$V_{CC} = 1.4 \text{ V}$ to 1.6 V		2.1	4.8	8.7	1.9	10.1	11.1	ns
		V <sub>CC</sub> = 1.65 V to 1.95 V		1.9	4.6	7.6	1.7	8.5	9.3	ns
		$V_{CC}$ = 2.3 V to 2.7 V		1.6	3.6	5.6	1.5	6.3	6.9	ns
		$V_{CC}$ = 3.0 V to 3.6 V		1.6	4.1	7.5	1.4	8.3	9.1	ns
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### Low-power 2-input NAND gate (open drain)

Symbol	Parameter	Conditions			25 °C		-4	0 °C to +1	25 °C	Unit
		-	Min	Typ <mark>[1]</mark>	Max	Min	Max (85 °C)	Max (125 °C)		
C <sub>L</sub> = 30	pF									
t <sub>pd</sub>	propagation delay	A or B to Y; see Figure 8	[2]							
		$V_{CC} = 0.8 V$		-	27.0	-	-	-	-	ns
		$V_{CC}$ = 1.1 V to 1.3 V		3.6	9.5	19.5	3.2	21.8	24.0	ns
		$V_{CC} = 1.4 \text{ V} \text{ to } 1.6 \text{ V}$		2.9	7.0	11.5	2.6	13.6	15.0	ns
		$V_{CC}$ = 1.65 V to 1.95 V		2.6	7.0	12.1	2.3	13.3	14.6	ns
		$V_{CC}$ = 2.3 V to 2.7 V		2.4	5.4	8.9	2.1	9.9	10.9	ns
		$V_{CC}$ = 3.0 V to 3.6 V		2.3	6.5	12.7	2.1	13.9	15.3	ns
C <sub>L</sub> = 5 p	F, 10 pF, 15 pF and	30 pF								
C <sub>PD</sub>	power dissipation capacitance	$f_i = 1 \text{ MHz};$ V <sub>I</sub> = GND to V <sub>CC</sub>	[3]							
		$V_{CC} = 0.8 V$		-	0.6	-	-	-	-	pF
		$V_{CC}$ = 1.1 V to 1.3 V		-	0.7	-	-	-	-	pF
		$V_{CC}$ = 1.4 V to 1.6 V		-	0.8	-	-	-	-	pF
		$V_{CC}$ = 1.65 V to 1.95 V		-	0.9	-	-	-	-	pF
		$V_{CC}$ = 2.3 V to 2.7 V		-	1.1	-	-	-	-	pF
		$V_{CC} = 3.0 \text{ V} \text{ to } 3.6 \text{ V}$		-	1.4	-	-	-	-	pF

### Table 8. Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V; for test circuit see Figure 9

[1] All typical values are measured at nominal  $V_{\mbox{CC}}.$ 

 $\label{eq:tpd} \ensuremath{\left[2\right]} \quad t_{pd} \mbox{ is the same as } t_{PZL} \mbox{ and } t_{PLZ}.$ 

[3]  $C_{PD}$  is used to determine the dynamic power dissipation (P<sub>D</sub> in  $\mu$ W).

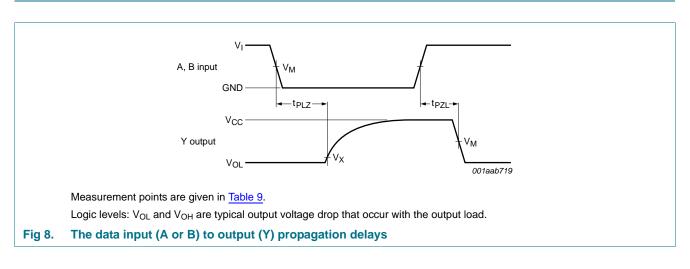
 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N$  where:

 $f_i = input frequency in MHz;$ 

 $V_{CC}$  = supply voltage in V;

N = number of inputs switching.

## 12. Waveforms



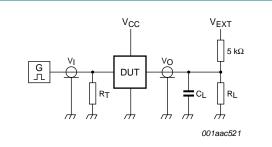
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### **NXP Semiconductors**

## 74AUP1G38

### Low-power 2-input NAND gate (open drain)

Table 9.Measurement po	ints		
Supply voltage	Input	Output	
V <sub>CC</sub>	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>
0.8 V to 1.6 V	$0.5\times V_{CC}$	$0.5\times V_{CC}$	V <sub>OL</sub> + 0.1 V
1.65 V to 2.7 V	$0.5\times V_{CC}$	$0.5\times V_{CC}$	V <sub>OL</sub> + 0.15 V
3.0 V to 3.6 V	$0.5\times V_{CC}$	$0.5\times V_{CC}$	V <sub>OL</sub> + 0.3 V



Test data is given in Table 10.

Definitions for test circuit:

R<sub>L</sub> = Load resistance.

 $C_L$  = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance should be equal to the output impedance  $Z_o$  of the pulse generator.

V<sub>EXT</sub> = External voltage for measuring switching times.

### Fig 9. Test circuit for measuring switching times

#### Table 10. Test data

Supply voltage	Load		V <sub>EXT</sub>		
V <sub>cc</sub>	CL	R <sub>L</sub> [1]	t <sub>PLH</sub> , t <sub>PHL</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>
0.8 V to 3.6 V	5 pF, 10 pF, 15 pF and 30 pF	5 k $\Omega$ or 1 M $\Omega$	open	GND	$2 \times V_{CC}$

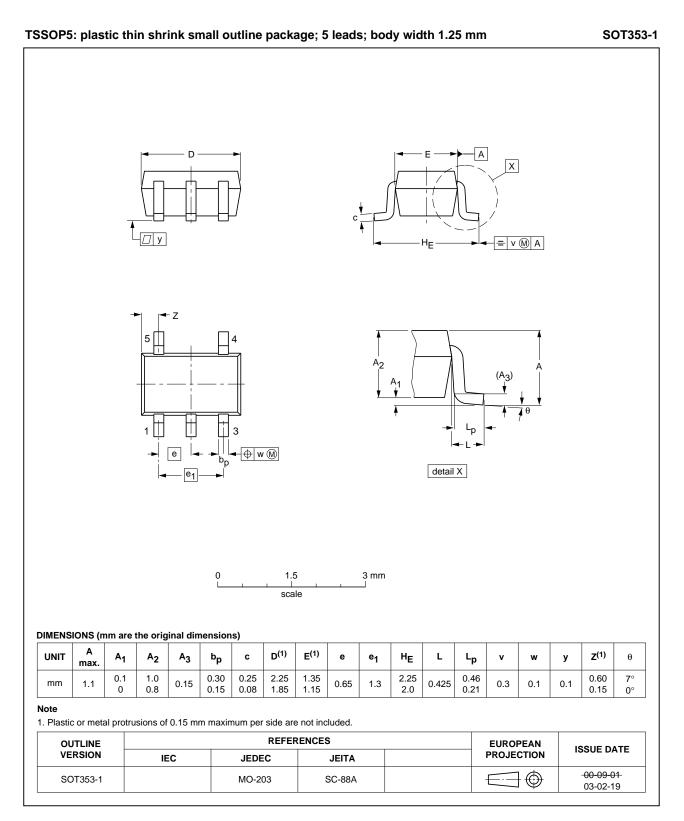
[1] For measuring enable and disable times  $R_L = 5 k\Omega$ , for measuring propagation delays, setup and hold times and pulse width  $R_L = 1 M\Omega$ .

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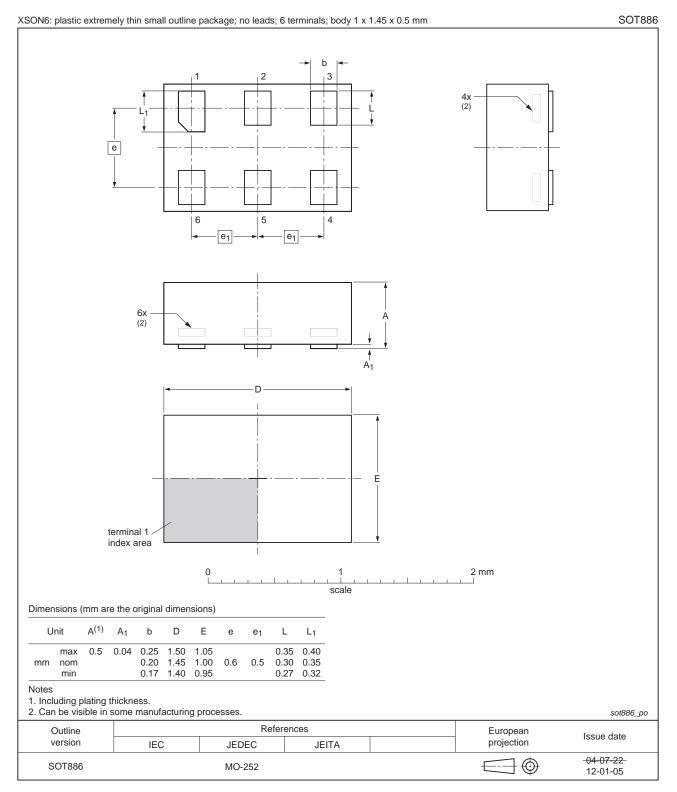
## 13. Package outline



### Fig 10. Package outline SOT353-1 (TSSOP5)

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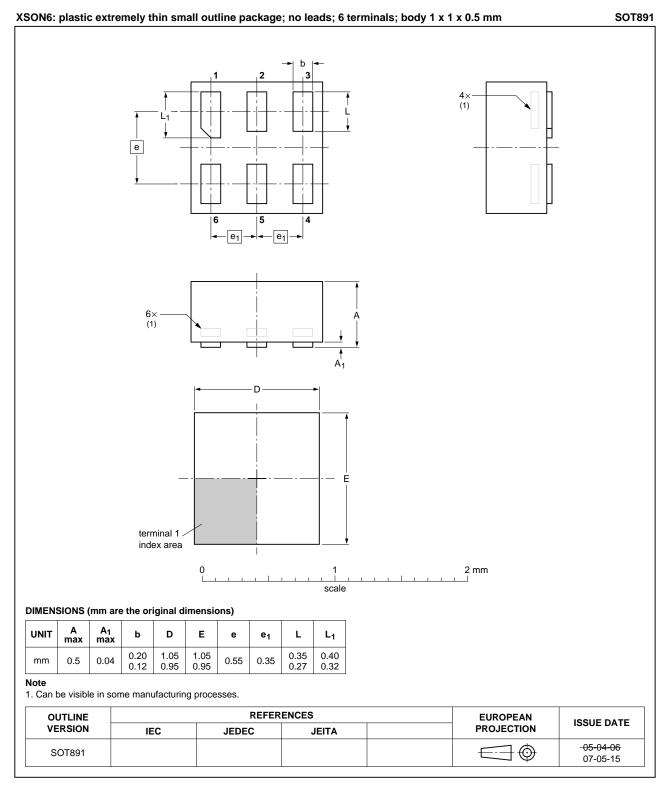
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### Fig 11. Package outline SOT886 (XSON6)

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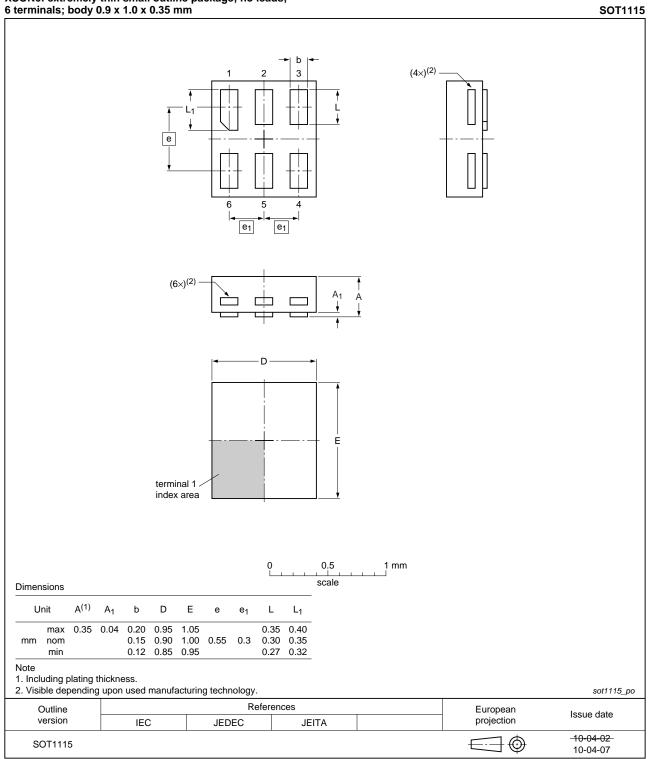
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### Fig 12. Package outline SOT891 (XSON6)

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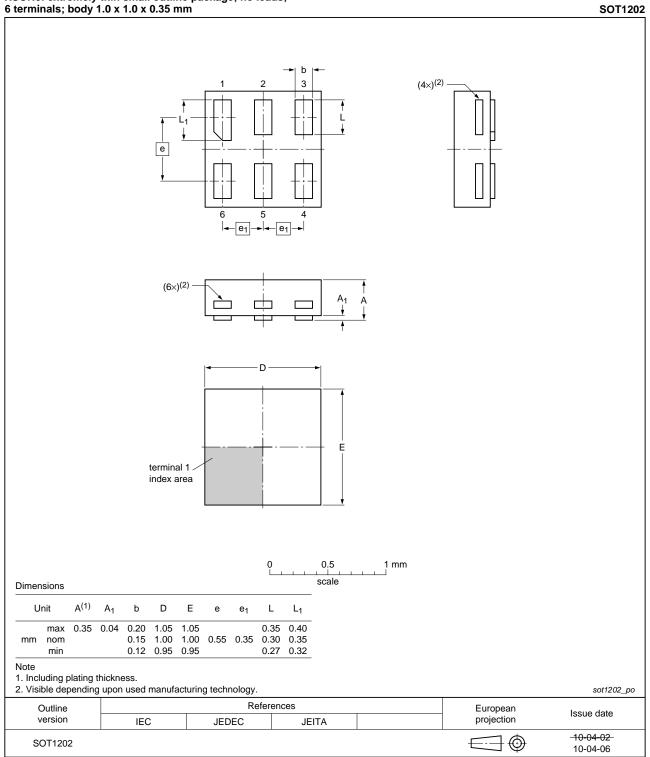


## XSON6: extremely thin small outline package; no leads; 6 terminals; body 0.9 x 1.0 x 0.35 mm

Fig 13. Package outline SOT1115 (XSON6)

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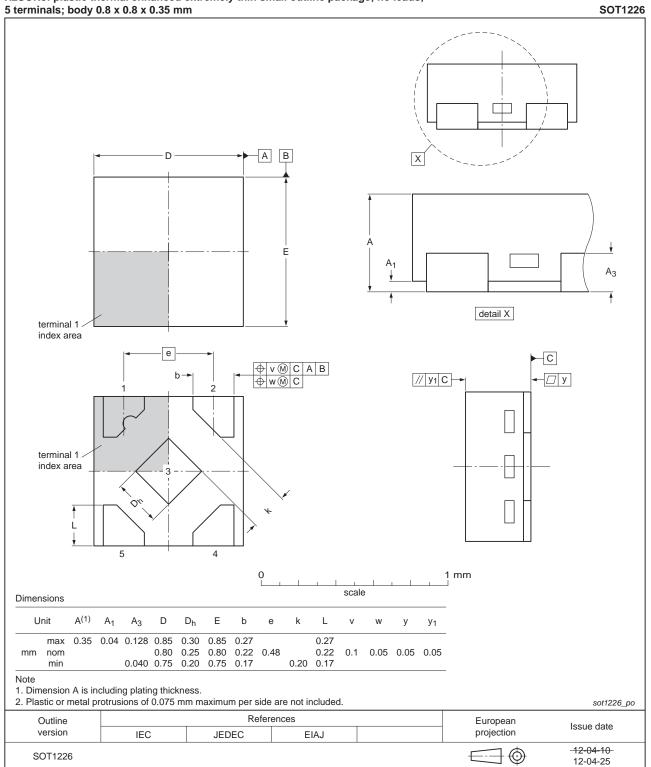


XSON6: extremely thin small outline package; no leads; 6 terminals; body 1.0 x 1.0 x 0.35 mm

Fig 14. Package outline SOT1202 (XSON6)

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X2SON5: plastic thermal enhanced extremely thin small outline package; no leads; 5 terminals; body 0.8 x 0.8 x 0.35 mm

### Fig 15. Package outline SOT1226 (X2SON5)

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## 14. Abbreviations

AcronymDescriptionCDMCharged Device ModelDUTDevice Under TestESDElectroStatic DischargeHBMHuman Body ModelMMMachine Model	Table 11. Abbreviations		
DUTDevice Under TestESDElectroStatic DischargeHBMHuman Body Model	Acronym	Description	
ESD     ElectroStatic Discharge       HBM     Human Body Model	CDM	Charged Device Model	
HBM Human Body Model	DUT	Device Under Test	
· · · · · · · · · · · · · · · · · · ·	ESD	ElectroStatic Discharge	
MM Machine Model	HBM	Human Body Model	
	MM	Machine Model	

## **15. Revision history**

Table 12. Revision	history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
74AUP1G38 v.6	20120628	Product data sheet	-	74AUP1G38 v.5
Modifications:	<ul> <li>Added type</li> </ul>	e number 74AUP1G38GX (	SOT1226)	
	<ul> <li>Package c</li> </ul>	outline drawing of SOT886 (	Figure 11) modified.	
74AUP1G38 v.5	20111129	Product data sheet	-	74AUP1G38 v.4
Modifications:	<ul> <li>Legal page</li> </ul>	es updated.		
74AUP1G38 v.4	20101007	Product data sheet	-	74AUP1G38 v.3
74AUP1G38 v.3	20090622	Product data sheet	-	74AUP1G38 v.2
74AUP1G38 v.2	20070614	Product data sheet	-	74AUP1G38 v.1
74AUP1G38 v.1	20061020	Product data sheet	-	-

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## 16. Legal information

### 16.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

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